


<b>Search Notes</b>  	<b>Application/Control No.</b>  10530404	<b>Applicant(s)/Patent Under Reexamination</b>  TAN ET AL.
	<b>Examiner</b>  CHRISTOPHER REVAK	<b>Art Unit</b>  2431

SEARCHED			
Class	Subclass	Date	Examiner
NONE	NONE	10/27/08	A.S

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCHED USPAT,USPGPUB,DERWENT,IBM-TDB,EPO, AND JPO WITH TEXT DELIMITERS	10/27/08	A.S
PALM Inventor Name Search	5/9/09	CR
BRS Text Search: USPAT, US PGPUB, USOCR, DERWENT, FPRS, IBM TDB, EPO, JPO (see attached search strategy)	5/9/09	CR
BRS Subclass Text Search: USPAT, US PGPUB (see attached search strategy)	5/9/09	CR
DIALOG Text Search: COMPSCI, ELECTRON, SOFTWARE (see attached search strategy)	5/9/09	CR
Interference Search (see attached search strategy)	5/9/09	CR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
726	1-5,14	5/9/09	CR
713	168-171,182	5/9/09	CR
380	270	5/9/09	CR

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